Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/750,580	HIGASHI ET AL.	
Examiner	Art Unit	
Thinh T Nauven	2818	

	SEARCHED					
Class	Subclass	Date	Examiner			
257	777	12/5/2005	TTN			
257	437	12/5/2005	TTN			
257	433	12/6/2005	TTN			
257	739	12/6/2005	TTN			
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST	12/5/2005	TTN		
EAST	12/6/2005	TTN		